Search Notes



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Applicant(s)/Patent Under Reexamination

YAMADA ET AL.

Examiner

Geib, Benjamin

Art Unit

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SEARCHED

| Class | Subclass | Date | Examiner |
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| 712 | 210 | 2/24/2009 | BPG |

| SEARCH NOTES | | |
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| Search Notes | Date | Examiner |
| Updated EAST search | 2/24/2009 | BPG |
| Inventor Name Search | 2/24/2009 | BPG |
| NPL search (Google Scholar and IEEE Xplore) | 2/24/2009 | BPG |

| | INTERFERENCE SEARC | н | |
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